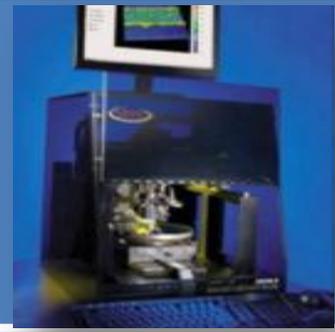




אוניברסיטת בן-גוריון בנגב
Ben-Gurion University
of the Negev

Nano-Fabrication
Center

Stylus Profilometer Dektak-8



Description

The Dektak 8 profiler contains the mechanical and optical components for sample placement, sample viewing, scanning/measurement and environmental protection. A diamond- or silicontipped stylus permits accurate measurements in a wide range of applications. In standard configuration, user programmable stylus force from 1 mg to 15 mg allows profiling on soft or hard surfaces. The *N-Lite* Option enables programmable stylus forces down to 0.03 mg.

Specifications / Capabilities

Performs contact-based 2D or 3D topography measurement to characterize film thickness, roughness, stress and defects on samples up to 200mm
Delivers 262 μm vertical range with 1 \AA vertical resolution at 6.55 μm range
Has Step Height Repeatability of 7.5 \AA step, 1 sigma
Allows Maximum sample thickness of 25.4mm

Link

<http://brukersupport.com/>

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